

Search Notes

Application/Control No.

10/688,935

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

OMIYA ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	240.99 345	11/7/2007	NT
396	348-350	11/7/2007	NT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	11/7/2007	NT
348/362 396/72-75 (text search - see search history printout)	11/8/2007	NT
Text search all classes - see search history printout	11/8/2007	NT